

MMC R&D: Thermal and Athermal Detector Experiment

Friedrich Wagner

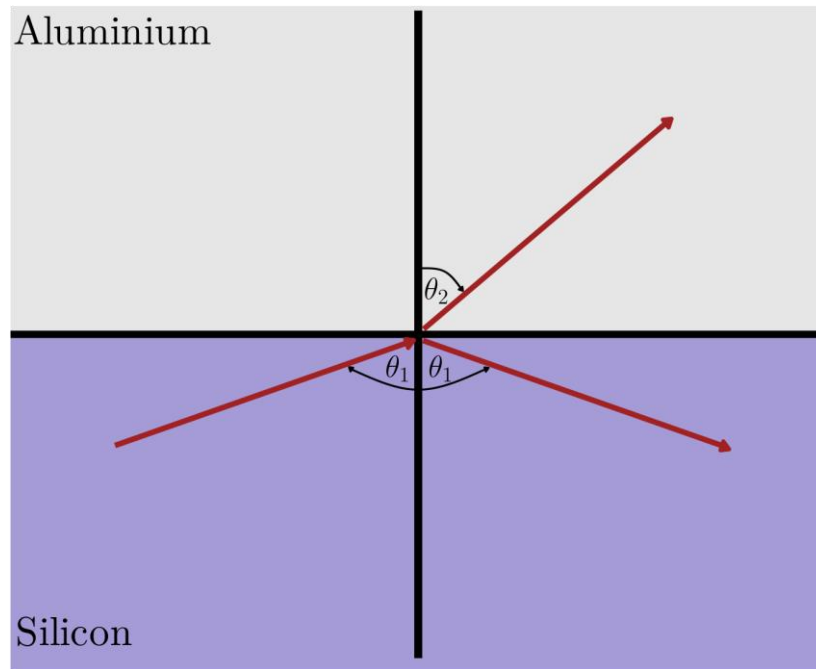
Institut für Mikro- und Nanoelektronische Systeme (IMS)

DELight Collaboration Meeting | Freiburg | 18th June, 2025

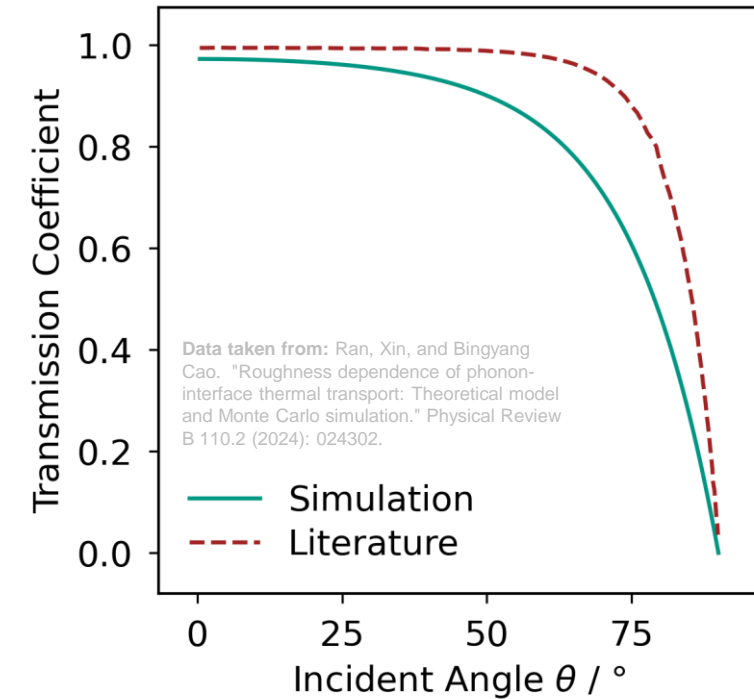


Rise Time Simulations – Athermal Detector

- Phonon collection time depends on transmission coefficient and collector coverage of crystal surface



Assuming flat surface and constant phonon velocities

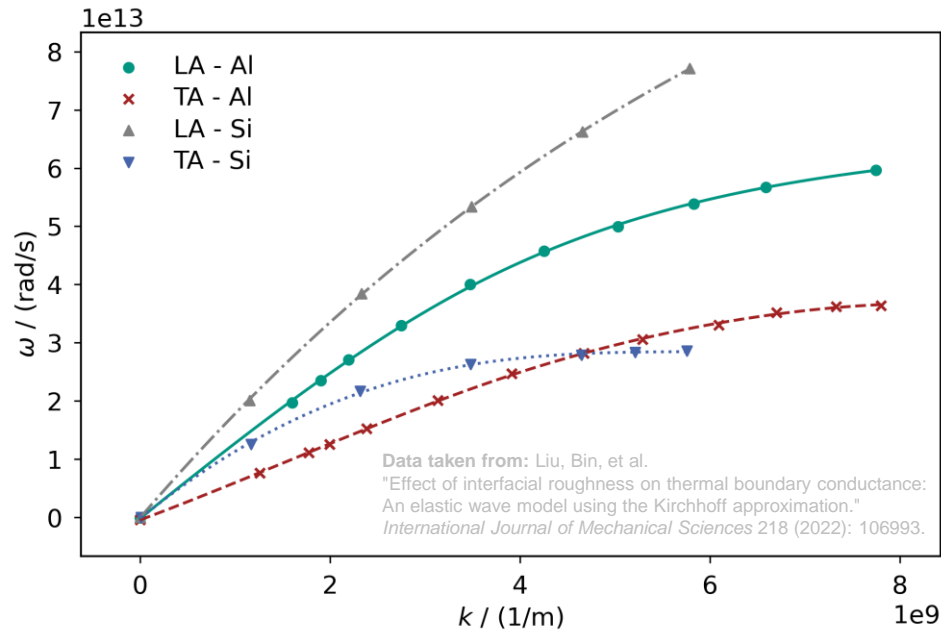


- Acoustic Mismatch Model:
 - Transmission coefficient depends on material densities, phonon velocities, and phonon incident angle.

Simulation values deviate significantly from literature 😞

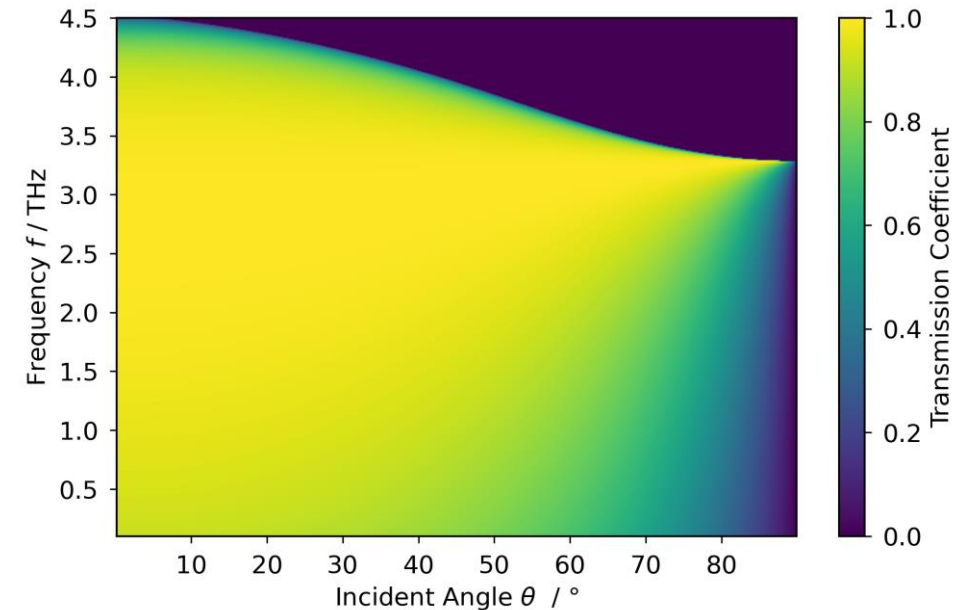
Rise Time Simulations – Phonon Frequency Consideration

Phonon Frequencies



- Calculate $v_g = \frac{\delta\omega}{\delta k}$ using Si/Al dispersion relation data

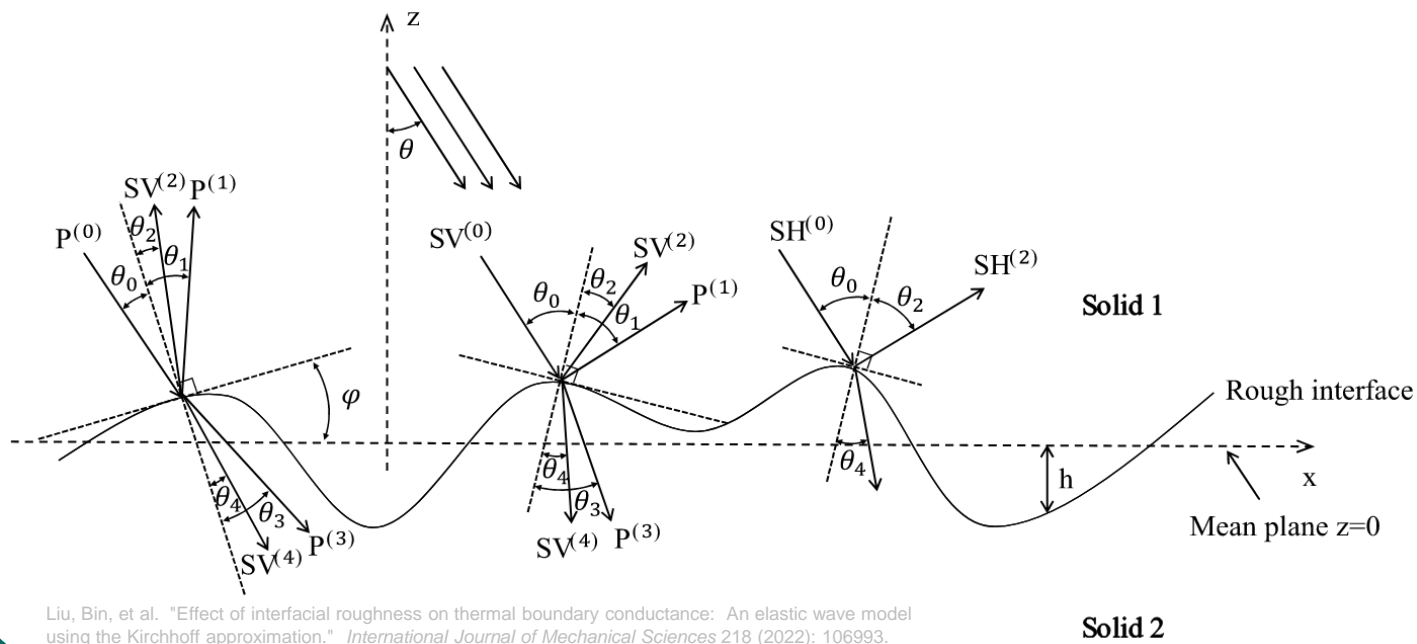
Transmission Coefficient



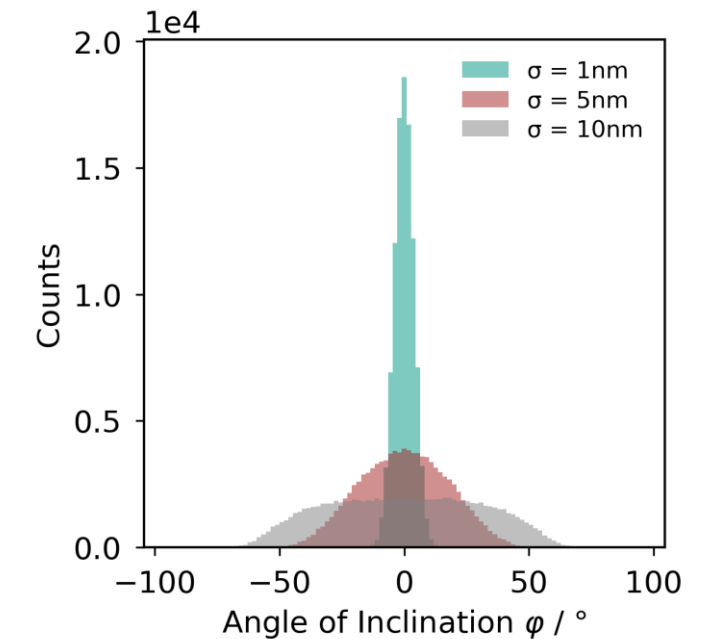
- Calculated with Acoustic Mismatch Model

Rise Time Simulations – Surface Roughness Consideration

Recalculation of incident angle (θ) dependent on angle of inclination (φ)

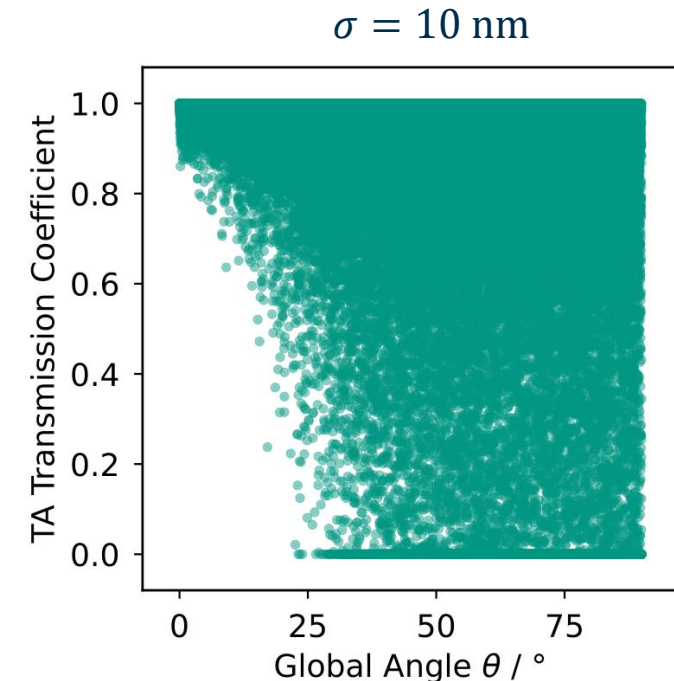
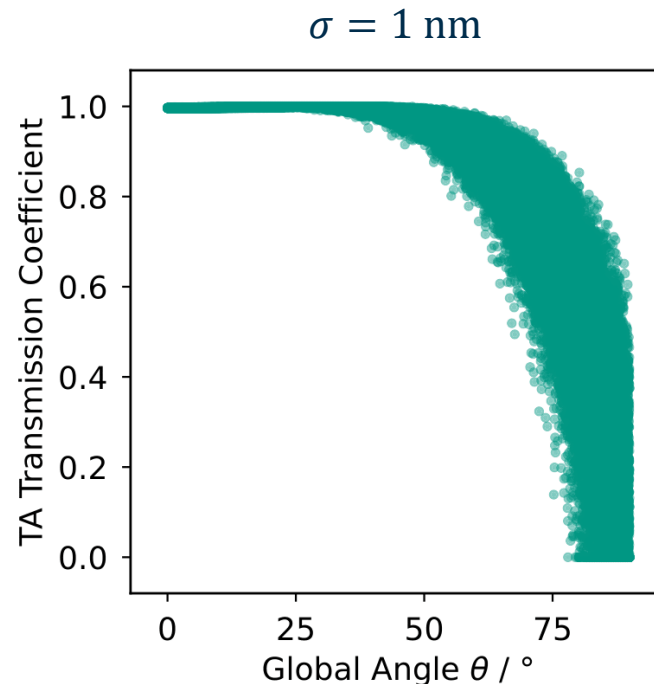
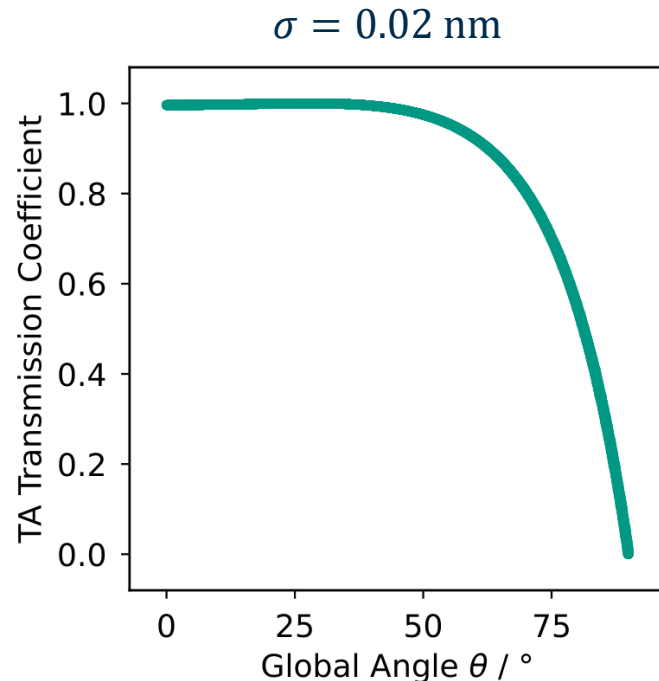


Distribution angle of inclination (φ)



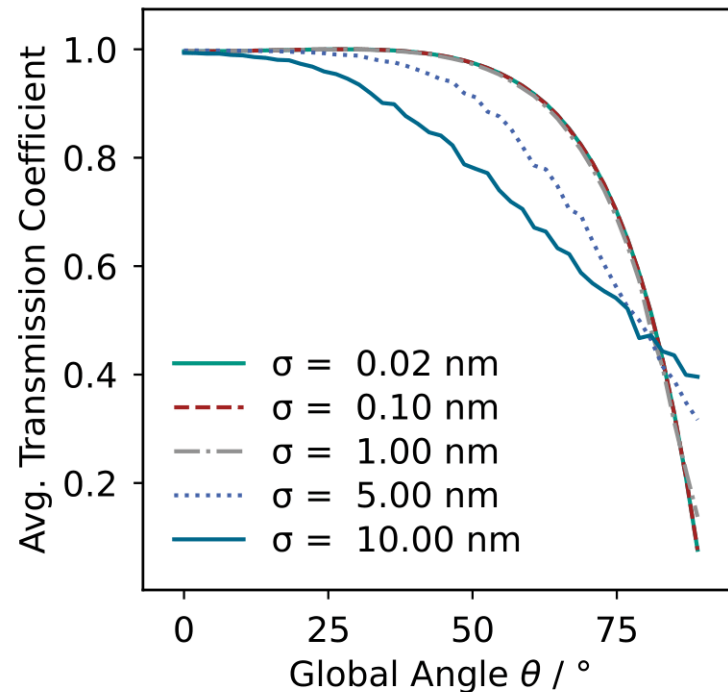
Rise Time Simulations – Surface Roughness Consideration

- Monte carlo simulation different surface roughnesses (σ):
 - Taking $n_\theta = 100000$ global incident angles (uniformly distributed between 0 and 90°)
 - Taking $n_\phi = 100000$ angles of inclination (using the gaussian distribution function)
 - Calculating actual incident angle and transmission coefficients using phonons with $f = 3.18$ THz



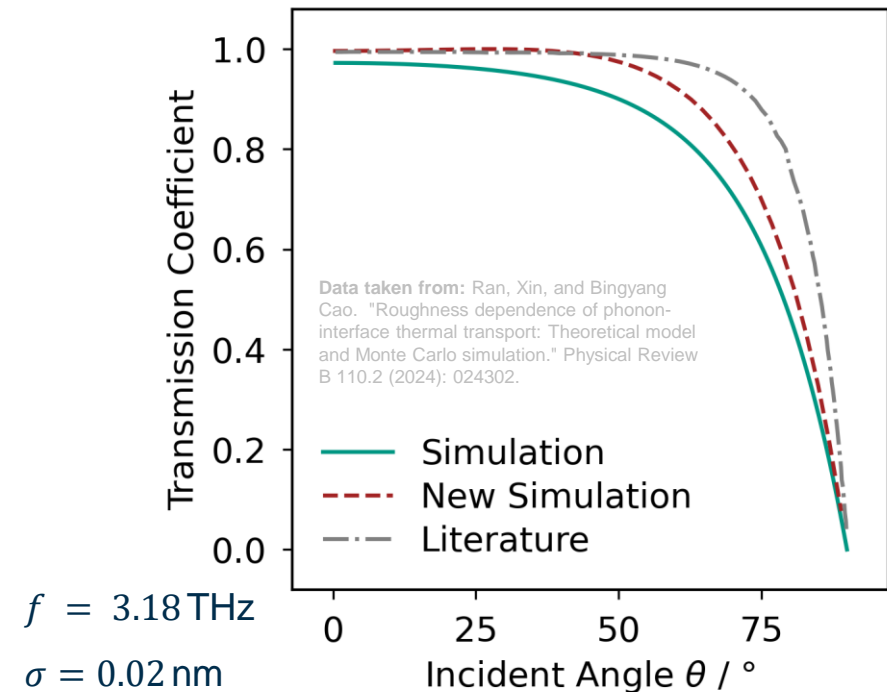
Rise Time Simulations – Transmission Coefficient

Taking the Transmission Coefficient Averages for All Incident Angles



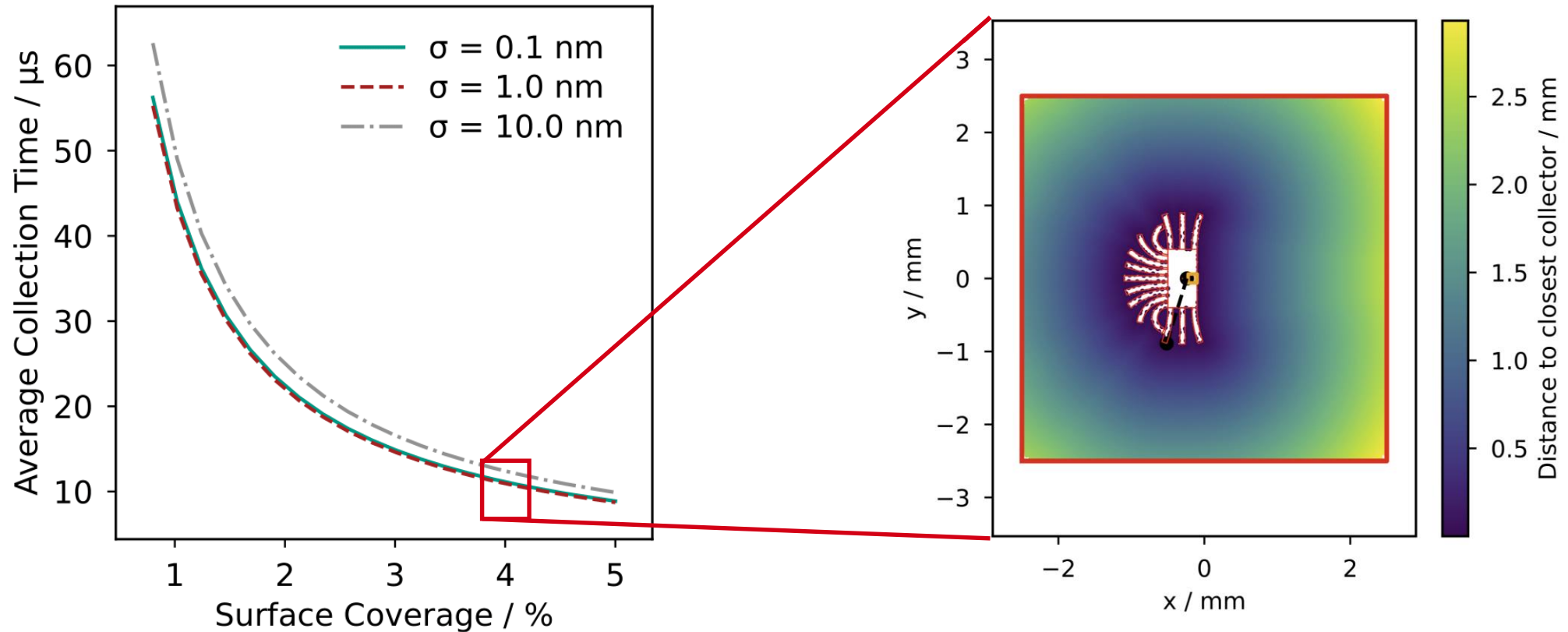
- A higher surface roughness results in a smaller transmission coefficient.

Comparison with Literature



- Not perfect but better

Rise Time Simulations – Prototype Athermal Detector

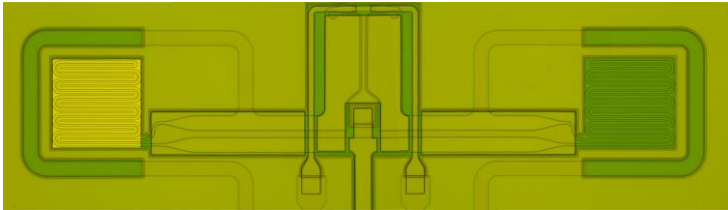
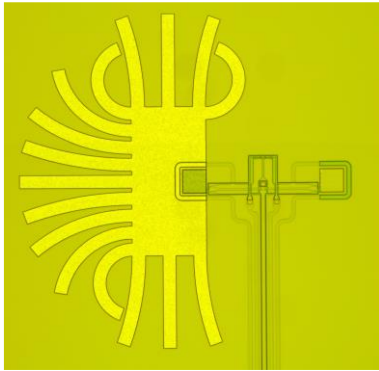


Using transmission coefficient to calculate phonon collection time

Prototype 4% collector coverage
~10 μs simulated rise time.

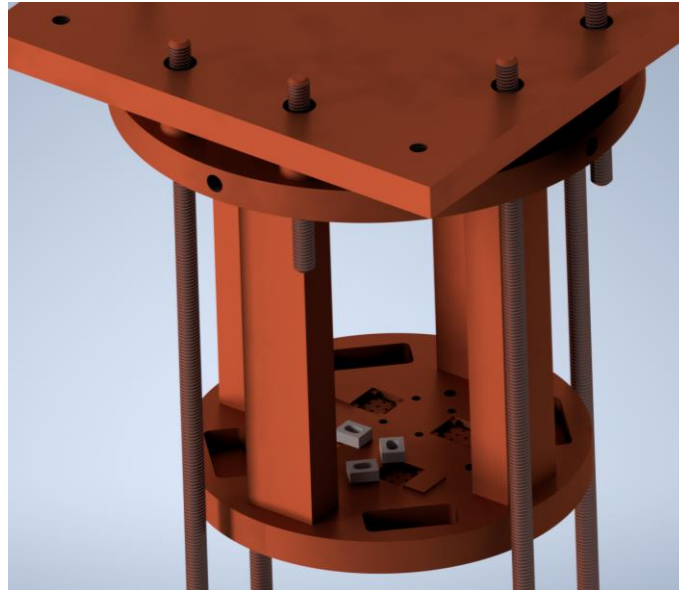
Current Status of the Experiment

Detector Chips



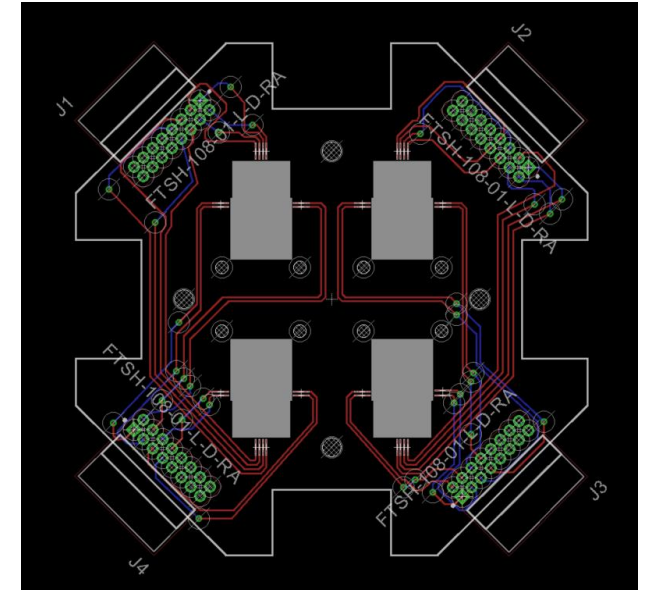
- Detector chips have been fabricated

Measurement Setup



- Measurement setup is currently in production by the workshop

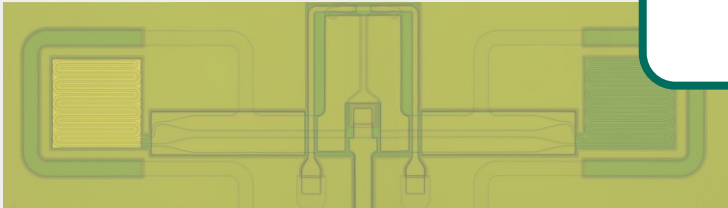
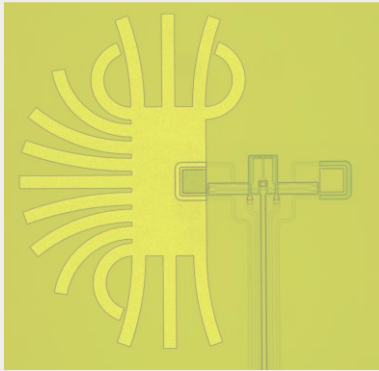
Custom PCB



- Custom printed circuit board has been designed

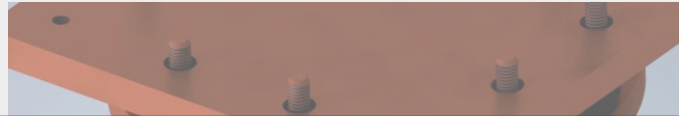
Current Status of the Experiment

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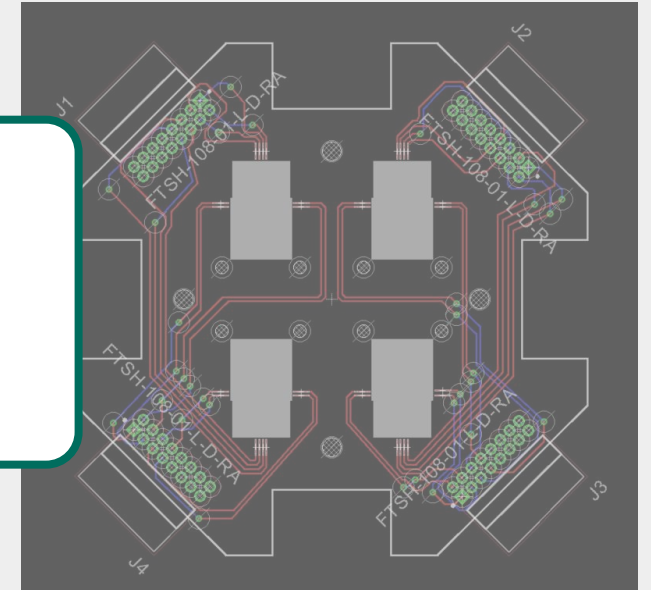
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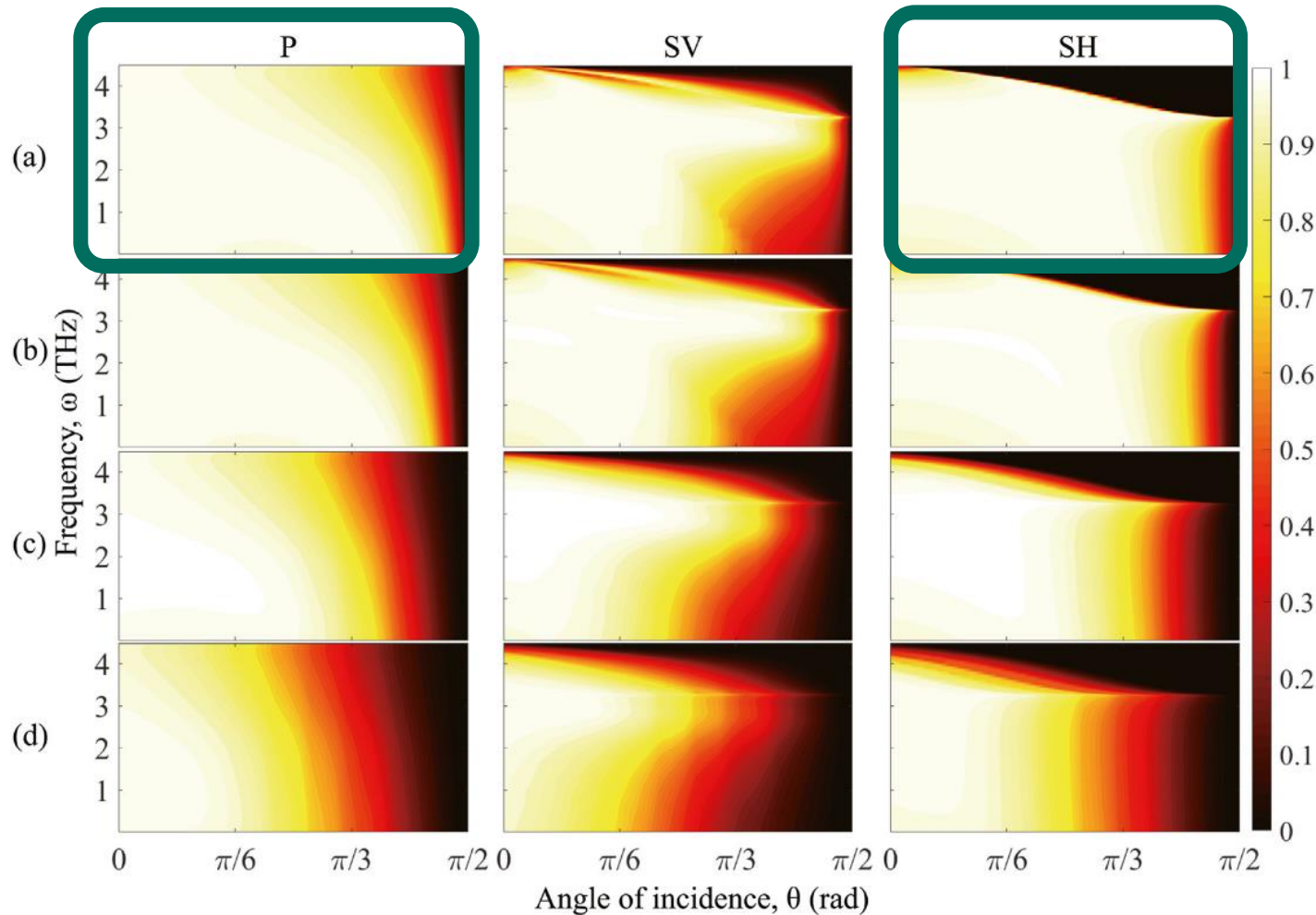
Measurement will take place in a few weeks!



Appendix: Acoustic Mismatch Model

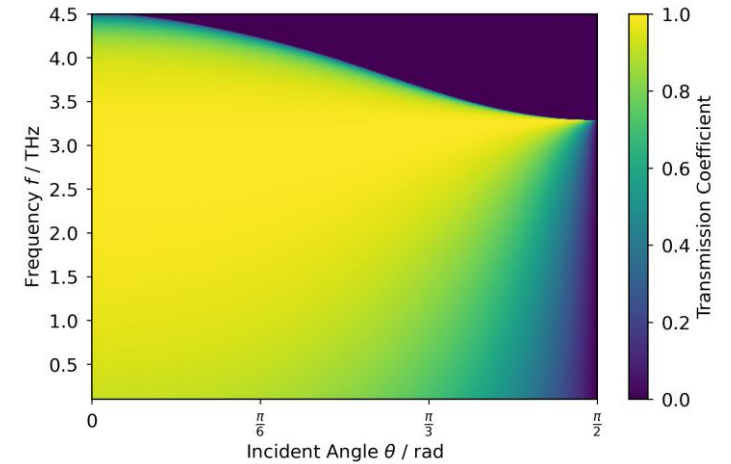
$$v_{1 \rightarrow 2} = \frac{4Z_1 Z_2 \cos(\theta_1) \cos(\theta_2)}{(Z_1 \cos(\theta_2) + Z_2 \cos(\theta_1))^2}$$

Appendix: Transmission Coefficient Frequency Dependence Literature



Liu, Bin, et al. "Effect of interfacial roughness on thermal boundary conductance: An elastic wave model using the Kirchhoff approximation." *International Journal of Mechanical Sciences* 218 (2022): 106993.

Transverse phonons



Longitudinal phonons



Appendix: Angle of Inclination Probability Distribution

$$P(\varphi) = \frac{1}{\sqrt{2\pi} \gamma \cos(\varphi)^2} \cdot \exp\left(\frac{-\tan(\varphi)^2}{2\gamma^2}\right)$$

with $\gamma = \frac{\sigma}{L}$

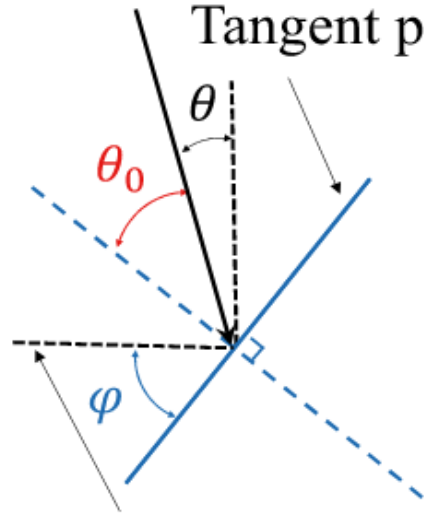
σ - surface roughness

L - correlation length, characterizes
the lateral variation of the height (set to 15 nm)

Appendix: Angle Recalculation

Incident wave

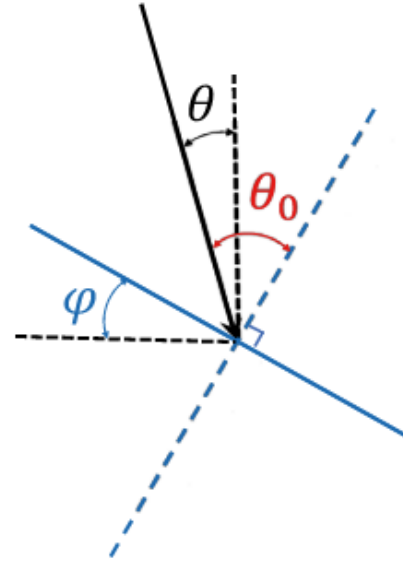
Tangent plane



Parallel to mean plane

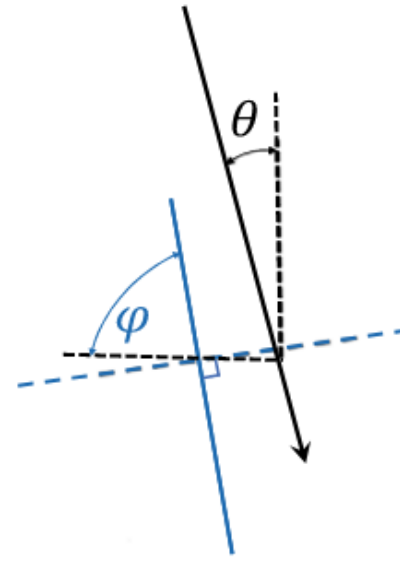
$$(1) -\frac{\pi}{2} \leq \varphi < -\theta$$

$$\theta_0 = -\theta - \varphi$$



$$(2) -\theta \leq \varphi < \frac{\pi}{2} - \theta$$

$$\theta_0 = \theta + \varphi$$

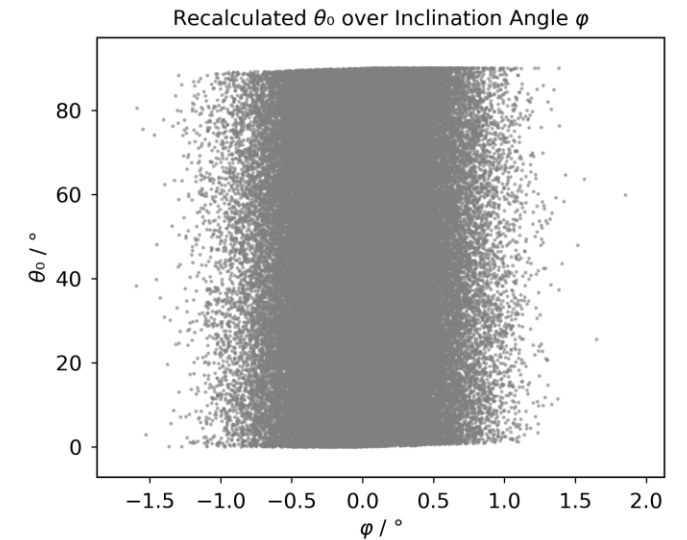
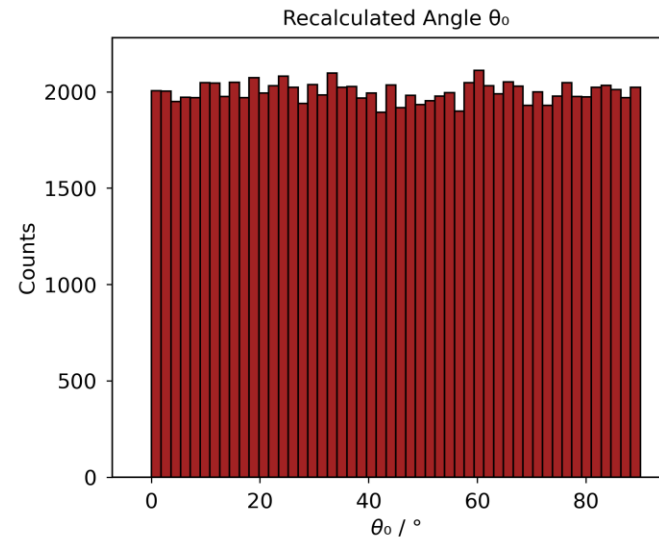
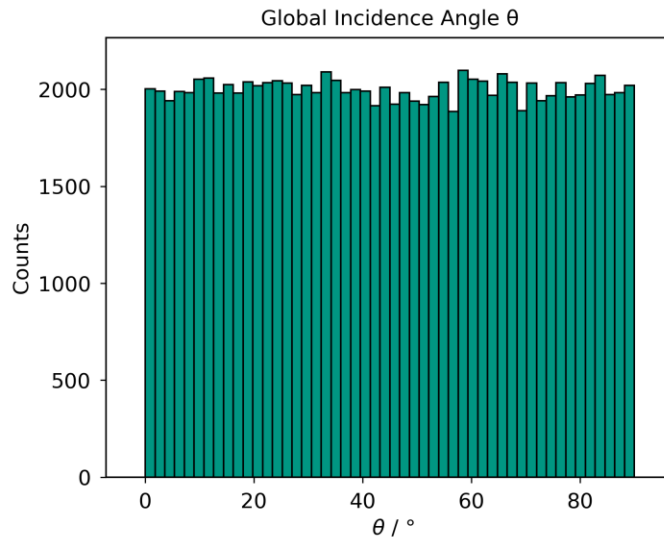


$$(3) \frac{\pi}{2} - \theta \leq \varphi < \frac{\pi}{2}$$

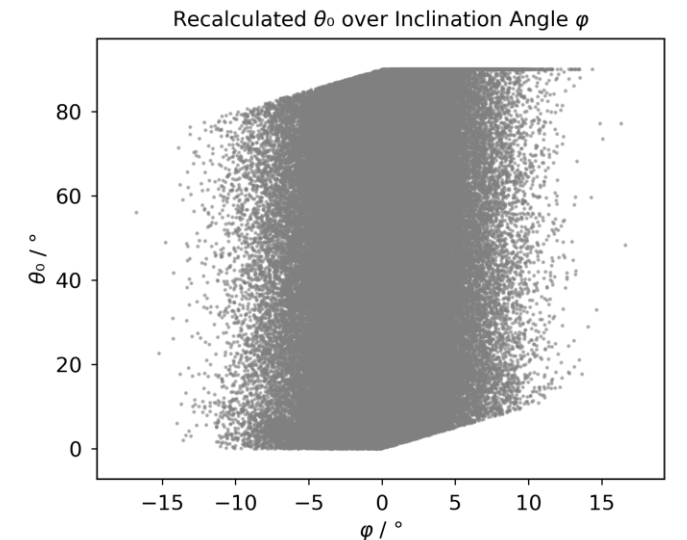
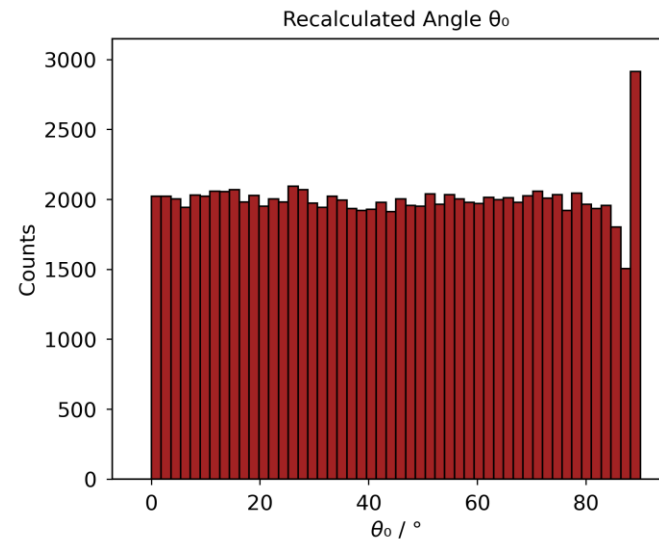
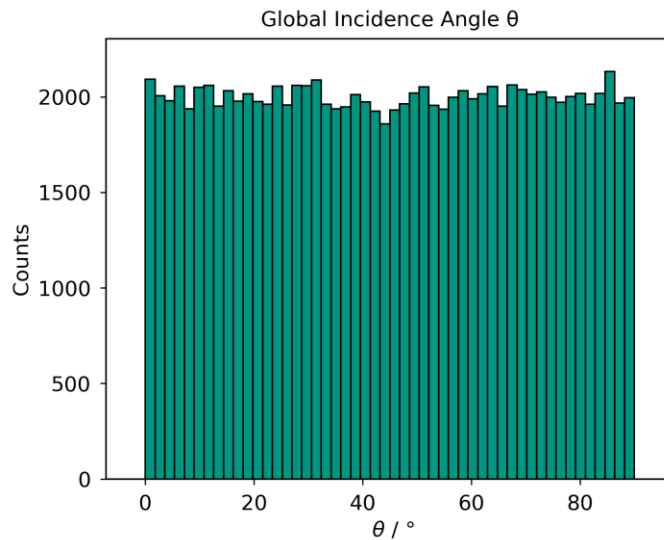
$$\text{Equivalent to } \theta_0 = \frac{\pi}{2}$$

Appendix: Angle Recalculation

$\sigma = 0.1 \text{ nm}$

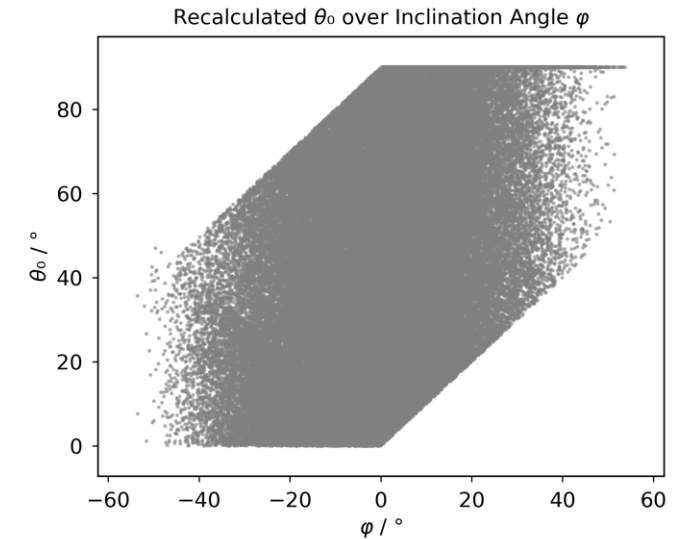
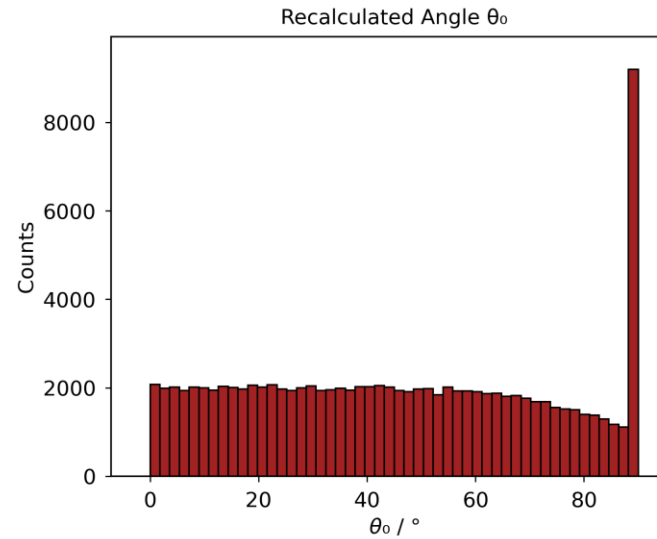
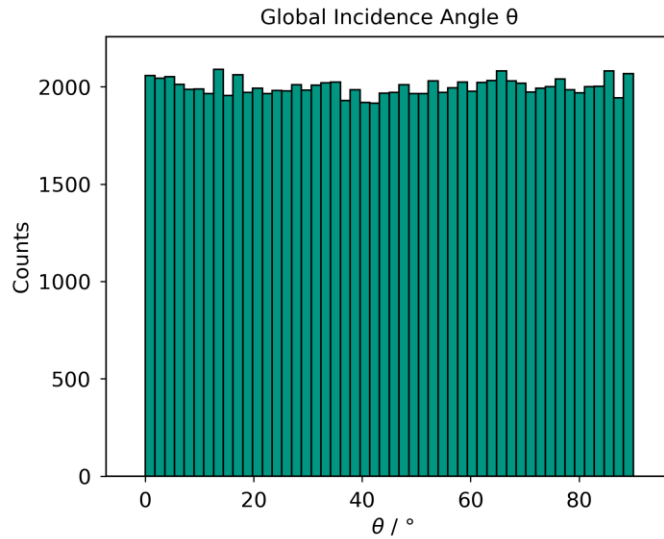


$\sigma = 1.0 \text{ nm}$

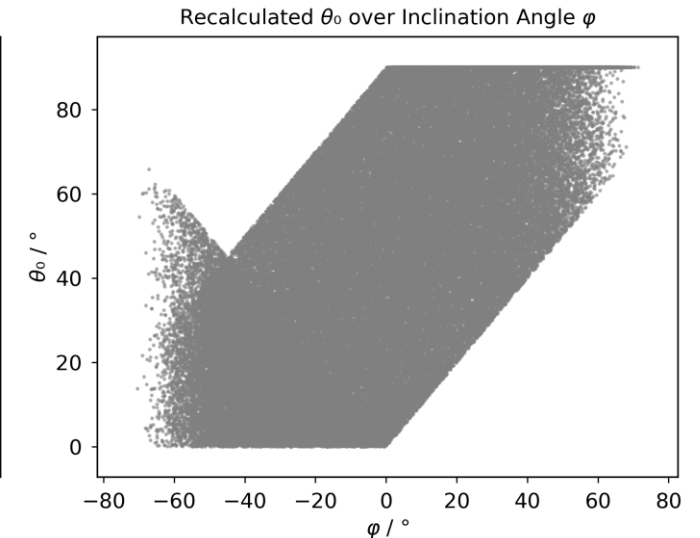
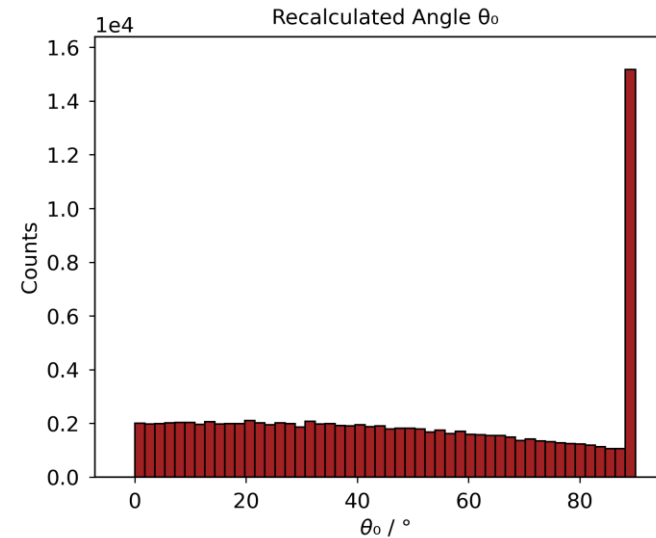
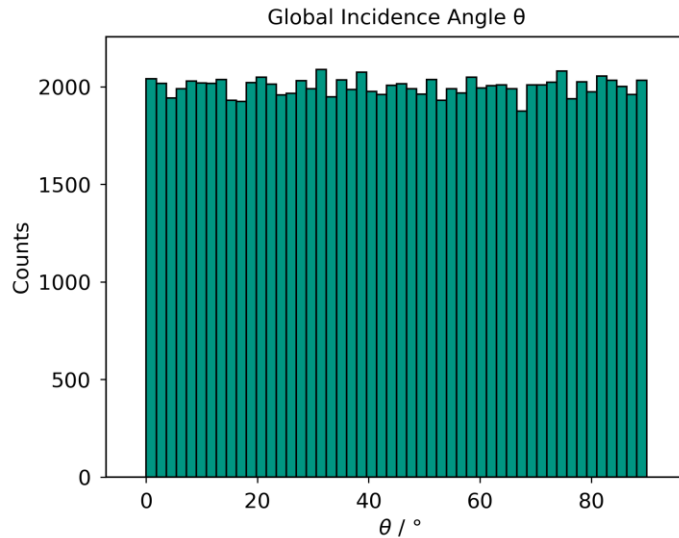


Appendix: Angle Recalculation

$\sigma = 5.0 \text{ nm}$

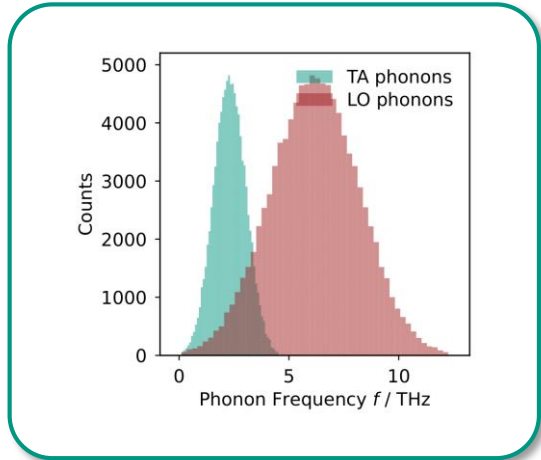


$\sigma = 10 \text{ nm}$

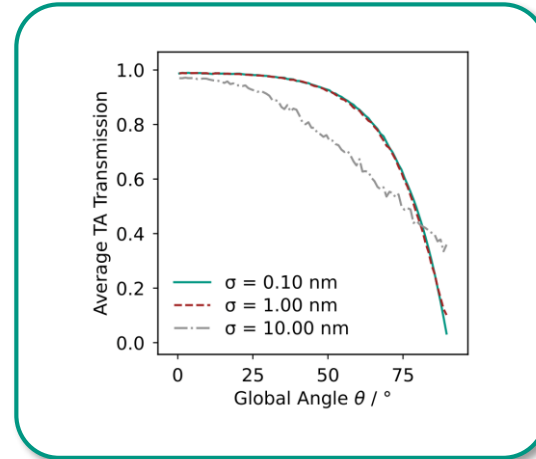
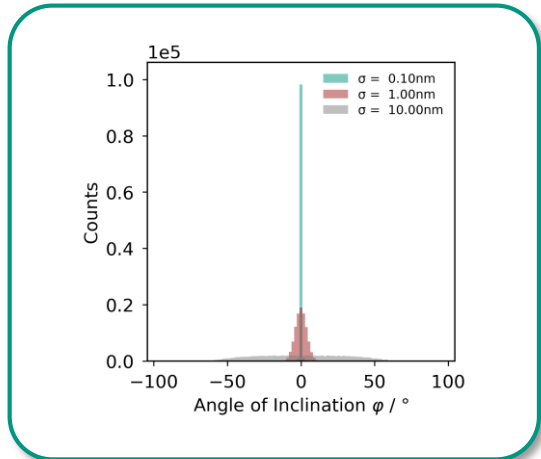


Appendix: Rise Time Calculation

Dummy Phonon frequency distribution



Surface Roughness – Angle Recalculation



$$p_{\text{abs}} = v_{\text{Si} \rightarrow \text{Al}} \cdot \xi$$

$$p_{\text{abs}} \cdot \sum_{i=0}^{n_{\text{refl}}} [1 - p_{\text{abs}}]^i > 0.90$$

$$\tau = n_{\text{refl}} \cdot \frac{2 \cdot d_{\text{wafer}}}{c_{\text{ph}}}$$

Use for each phonon its frequency dependent velocity

